CLAIMS

1. A housing for a prober having a multi-layer structure in which a plurality of measuring parts are stacked in multiple stages and a moving stage is configured to be movable among two or more measuring parts arranged on a same layer, the housing for a prober comprising:

floor bases configured to constitute floor surfaces of respective layers of the multi-layer structure; and

a side frame body which is arranged between a floor base of one layer and a floor base of another layer positioned above the one layer among the plurality of layers, and positioned in both side parts of the measuring parts, wherein

the side frame body includes:

a first side frame which is erected on the floor base of the one layer and supports a lower surface side of the floor base of the another layer; and

a second side frame which is erected on the floor base of the one layer at a position different from that of the first side frame, and supports a measuring part constituent member arranged in each measuring part, and

the second side frame has a gate form comprising two column parts and a beam part which spans between the two column parts, in such a manner that the moving stage is movable among two or more measuring parts on the one layer.

2. The housing for a prober according to claim 1, wherein

the side frame body is arranged on a layer other than an uppermost layer among the plurality of layers.

3. The housing for a prober according to claim 2, further comprising

a head plate having a holding unit configured to hold the measuring part constituent member, wherein

a lower surface side of the head plate is supported by the second side frame.

4. The housing for a prober according to any one of claims 1 to 3, wherein

the second side frame is juxtaposed to the first side frame at a position adjacent to the first side frame.

5. The housing for a prober according to any one of claims 1 to 4, wherein

the measuring part constituent member is one of a pogo frame, a probe card and a test head.

6. The housing for a prober according to any one of claims 1 to 5, wherein

the floor base of the one layer has a flat plate shape which is elongated in a first direction and parallel to a horizontal plane,

the moving stage is movable in the first direction on the one layer, and

in the second side frame, the beam extends in a second direction different from the first direction on the horizontal plane.

7. A prober comprising

the housing for a prober according to any one of claims 1 to 6, wherein

two or more measuring parts are provided on the one layer, and

the prober comprises a moving stage capable of moving a wafer to be inspected to each of the two or more measuring parts arranged on the one layer.